•	Application No.	Applicant(s)
Notice of Allowability	10/699,047 Examiner	KIM, JI-YOUNG Art Unit
•		2822
The MAILING DATE of this communication apperature of the communication appearance of the co	(OR REMAINS) CLOSED in or other appropriate commits (GHTS). This application is	th the correspondence address n this application. If not included unication will be mailed in due course. THIS
1. \boxtimes This communication is responsive to <u>the amendment filed</u>	December 11, 2006.	
2. The allowed claim(s) is/are 8-15 and 17-26.		
3. The drawings filed on 30 October 2003 are accepted by the	e Examiner.	•
 4. Acknowledgment is made of a claim for foreign priority up a) All b) Some* c) None of the: 1. Certified copies of the priority documents have 2. Certified copies of the priority documents have 3. Copies of the certified copies of the priority do International Bureau (PCT Rule 17.2(a)). * Certified copies not received: 	e been received. e been received in Application	on No
Applicant has THREE MONTHS FROM THE "MAILING DATE" noted below. Failure to timely comply will result in ABANDONN THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.		e a reply complying with the requirements
5. A SUBSTITUTE OATH OR DECLARATION must be subminformal PATENT APPLICATION (PTO-152) which give		
6. CORRECTED DRAWINGS (as "replacement sheets") mus	st be submitted.	
(a) ☐ including changes required by the Notice of Draftsperson's Patent Drawing Review (PTO-948) attached		
1) 🗌 hereto or 2) 🔲 to Paper No./Mail Date		
(b) ☐ including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No./Mail Date		
Identifying indicia such as the application number (see 37 CFR 1 each sheet. Replacement sheet(s) should be labeled as such in t		
7. DEPOSIT OF and/or INFORMATION about the depo attached Examiner's comment regarding REQUIREMENT	SIT OF BIOLOGICAL MAT FOR THE DEPOSIT OF BIO	ERIAL must be submitted. Note the DLOGICAL MATERIAL.
Attachment(s) 1. ☐ Notice of References Cited (PTO-892) 2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948) 3. ☐ Information Disclosure Statements (PTO-1449 or PTO/SB/C Paper No./Mail Date 4. ☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material	6. Interview S Paper No. 98), 7. Examiner's	formal Patent Application (PTO-152) ummary (PTO-413), 'Mail Date Amendment/Comment Statement of Reasons for Allowance

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DETAILED ACTION

Response to Amendment

This office action is in response to the amendment filed December 11, 2006.

Accordingly, claims 8, 20 and 25 were amended. Claims 1-7 and 16 were previously canceled.

Currently, claims 8-15 and 17-26 remain pending.

Response to Arguments

Applicant's arguments, see REMARKS, pages 6-9, filed in the amendment, with respect to the rejections of claims 8-15 and 17-26 under Weis, Tabata and Ishikawa have been fully considered and are persuasive. The rejections thereof have been withdrawn.

Allowable Subject Matter

Claims 8-15 and 17-26 are allowed.

The following is an examiner's statement of reasons for allowance: none of the prior art of record fairly shows or suggests all the process limitations as claimed.

Re claim 8, none of the prior art of record discloses the following limitations in combination with the rest of the limitations in the claim: forming a gate electrode having a first portion which rises over the semiconductor substrate and a second portion filling the trench by successively patterning the capping layer and the gate conductive layer, wherein the first portion has a smaller width than that of the second portion.

Re claim 20, none of the prior art of record discloses the following limitations in combination with the rest of the limitations in the claim: forming a gate electrode having a first portion which rises over the semiconductor substrate and a second portion filling the trench by

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successively patterning the capping layer and the gate conductive layer, wherein the first portion has a smaller width than that of the second portion.

Re claim 25, none of the prior art of record discloses the following limitations in combination with the rest of the limitations in the claim: forming a gate electrode having a first portion which rises over the semiconductor substrate and a second portion filling the trench by successively patterning the capping layer and the gate conductive layer, wherein the first portion has a smaller width than that of the second portion, and wherein forming the gate electrode comprises recessing the gate conductive layer that fills the trench to a depth of 500 Angstroms or less from the surface of the semiconductor substrate.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Khanh B. Duong whose telephone number is (571) 272-1836. The examiner can normally be reached on Monday to Friday from 8:00 AM to 5:00 PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Zandra Smith can be reached on (571) 272-2429. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

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KBD

Supervisory Patent Examiner

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